

TOSHIBA BIPOLAR DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

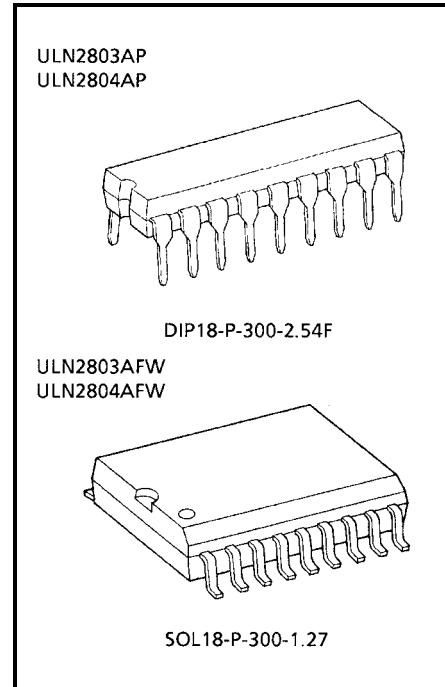
**ULN2803AP,ULN2803AFW,ULN2804AP,ULN2804AFW
(Manufactured by Toshiba Malaysia)****8CH DARLINGTON SINK DRIVER**

The ULN2803AP / AFW Series are high-voltage, high-current darlington drivers comprised of eight NPN darlington pairs. All units feature integral clamp diodes for switching inductive loads.

Applications include relay, hammer, lamp and display (LED) drivers.

FEATURES

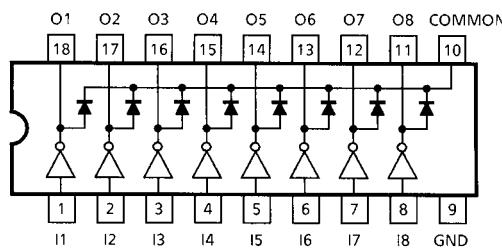
- Output current (single output)
500 mA (Max.)
- High sustaining voltage output
50 V (Min.)
- Output clamp diodes
- Inputs compatible with various types of logic.
- Package Type-AP : DIP-18pin
- Package Type-AFW : SOL-18pin



Weight
DIP18-P-300-2.54F: 1.478 g (Typ.)
SOL18-P-300-1.27 : 0.48 g (Typ.)

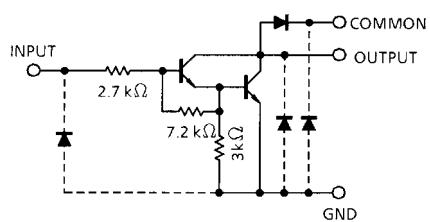
PIN CONNECTION (TOP VIEW)

TYPE	INPUT BASE RESISTOR	DESIGNATION
ULN2803AP / AFW	2.7 kΩ	TTL, 5 V CMOS
ULN2804AP / AFW	10.5 kΩ	6~15 V PMOS, CMOS

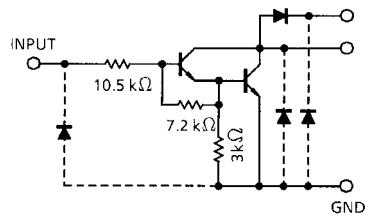


SCHEMATICS (EACH DRIVER)

ULN2803AP / AFW



ULN2804AP / AFW



Note: The input and output parasitic diodes cannot be used as clamp diodes.

MAXIMUM RATINGS ($T_a = 25^\circ\text{C}$)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Output Sustaining Voltage	$V_{CE}(\text{SUS})$	-0.5~50	V
Output Current	I_{OUT}	500	mA / ch
Input Voltage	V_{IN}	-0.5~30	V
Clamp Diode Reverse Voltage	V_R	50	V
Clamp Diode Forward Current	I_F	500	mA
Power Dissipation	P_D	1.47	W
		0.92 / 1.31 (Note)	
Operating Temperature	T_{opr}	-40~85	°C
Storage Temperature	T_{stg}	-55~150	°C

Note: On Glass Epoxy PCB (75 × 114 × 1.6 mm Cu 20%)

RECOMMENDED OPERATING CONDITIONS (Ta = -40~85°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN	TYP.	MAX	UNIT	
Output Sustaining Voltage		V _{CE} (SUS)		0	—	50	V	
Output Current	AP	I _{OUT}	T _{pw} = 25 ms, Duty = 10%, 8 Circuits	0	—	347	mA / ch	
			T _{pw} = 25 ms, Duty = 50%, 8 Circuits	0	—	123		
	AFW		T _{pw} = 25 ms, Duty = 10%, 8 Circuits	0	—	268		
			T _{pw} = 25 ms, Duty = 50%, 8 Circuits	0	—	90		
Input Voltage		V _{IN}		0	—	30	V	
Input Voltage (Output On)	ULN2803AP / AFW	V _{IN} (ON)		3.5	—	30	V	
	ULN2804AP / AFW			8	—	30		
Clamp Diode Reverse Voltage		V _R		—	—	50	V	
Clamp Diode Forward Current		I _F		—	—	400	mA	
Power Dissipation	AP	P _D	T _a = 85°C	—	—	0.76	W	
	AFW		T _a = 85°C (Note)	—	—	0.48		

Note: On Glass Epoxy PCB (75 × 114 × 1.6 mm Cu 20%)

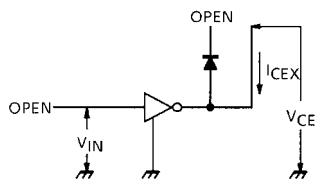
ELECTRICAL CHARACTERISTICS ($T_a = 25^\circ\text{C}$)

CHARACTERISTIC	SYMBOL	TEST CIR-CUIT	TEST CONDITION	MIN	TYP.	MAX	UNIT
Output Leakage Current ULN2804AP / AFW	I_{CEX}	1	$V_{CE} = 50 \text{ V}$, $T_a = 25^\circ\text{C}$	—	—	50	μA
			$V_{CE} = 50 \text{ V}$, $T_a = 85^\circ\text{C}$	—	—	100	
			$V_{CE} = 50 \text{ V}$, $V_{IN} = 1 \text{ V}$	—	—	500	
Collector-Emitter Saturation Voltage	$V_{CE} (\text{sat})$	2	$I_{OUT} = 350 \text{ mA}$, $I_{IN} = 500 \mu\text{A}$	—	1.3	1.6	V
			$I_{OUT} = 200 \text{ mA}$, $I_{IN} = 350 \mu\text{A}$	—	1.1	1.3	
			$I_{OUT} = 100 \text{ mA}$, $I_{IN} = 250 \mu\text{A}$	—	0.9	1.1	
Input Current ULN2803AP / AFW ULN2804AP / AFW	$I_{IN} (\text{ON})$	2	$V_{IN} = 3.85 \text{ V}$	—	0.93	1.35	mA
			$V_{IN} = 5 \text{ V}$	—	0.35	0.5	
			$V_{IN} = 12 \text{ V}$	—	1.0	1.45	
	$I_{IN} (\text{OFF})$	4	$I_{OUT} = 500 \mu\text{A}$, $T_a = 85^\circ\text{C}$	50	65	—	μA
Input Voltage (Output On)	ULN2803AP / AFW ULN2804AP / AFW	5	$V_{CE} = 2 \text{ V}$, $I_{OUT} = 200 \text{ mA}$	—	—	2.4	V
			$V_{CE} = 2 \text{ V}$, $I_{OUT} = 250 \text{ mA}$	—	—	2.7	
			$V_{CE} = 2 \text{ V}$, $I_{OUT} = 300 \text{ mA}$	—	—	3.0	
			$V_{CE} = 2 \text{ V}$, $I_{OUT} = 125 \text{ mA}$	—	—	5.0	
			$V_{CE} = 2 \text{ V}$, $I_{OUT} = 200 \text{ mA}$	—	—	6.0	
			$V_{CE} = 2 \text{ V}$, $I_{OUT} = 275 \text{ mA}$	—	—	7.0	
			$V_{CE} = 2 \text{ V}$, $I_{OUT} = 350 \text{ mA}$	—	—	8.0	
DC Current Transfer Ratio	h_{FE}	2	$V_{CE} = 2 \text{ V}$, $I_{OUT} = 350 \text{ mA}$	1000	—	—	
Clamp Diode Reverse Current	I_R	6	$T_a = 25^\circ\text{C}$ (Note)	—	—	50	μA
			$T_a = 85^\circ\text{C}$ (Note)	—	—	100	
Clamp Diode Forward Voltage	V_F	7	$I_F = 350 \text{ mA}$	—	—	2.0	V
Input Capacitance	C_{IN}	—		—	15	—	pF
Turn-On Delay	t_{ON}	8	$R_L = 125 \Omega$, $V_{OUT} = 50 \text{ V}$	—	0.1	—	μs
Turn-Off Delay	t_{OFF}		$R_L = 125 \Omega$, $V_{OUT} = 50 \text{ V}$	—	0.2	—	

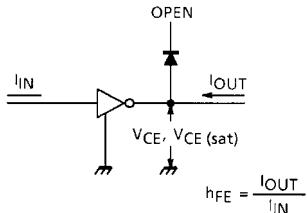
Note: $V_R = V_R \text{ MAX.}$

TEST CIRCUIT

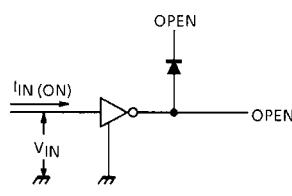
1. I_{CEX}



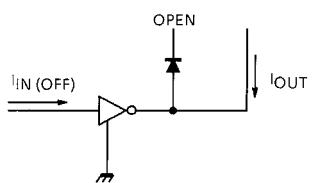
2. $V_{CE}(\text{sat}), h_{FE}$



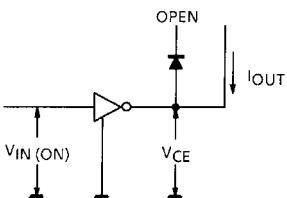
3. $I_{IN}(\text{ON})$



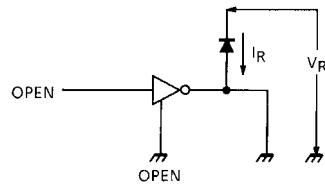
4. $I_{IN}(\text{OFF})$



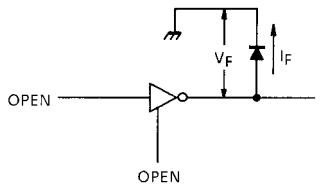
5. $V_{IN}(\text{ON})$

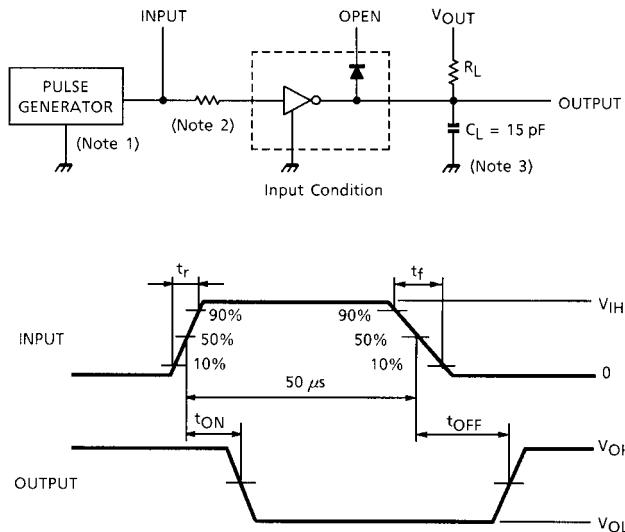


6. I_R



7. V_F



8. t_{ON} , t_{OFF} 

Note 1: Pulse Width 50 μ s, Duty Cycle 10%

Output Impedance 50 Ω , $t_r \leq 5$ ns, $t_f \leq 10$ ns

Note 2: See below.

INPUT CONDITION

TYPE NUMBER	R1	V _{IH}
ULN2803AP / AFW	0 Ω	3 V
ULN2804AP / AFW	0 Ω	8 V

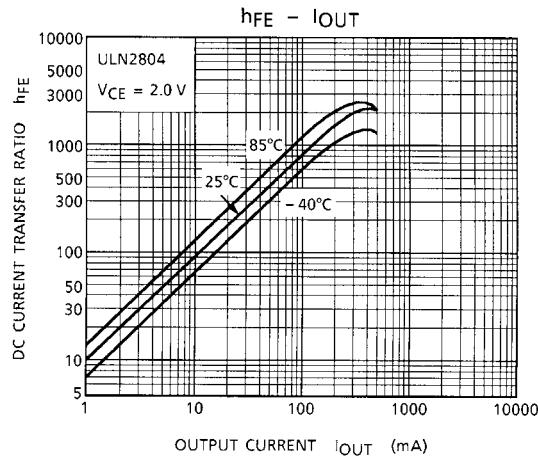
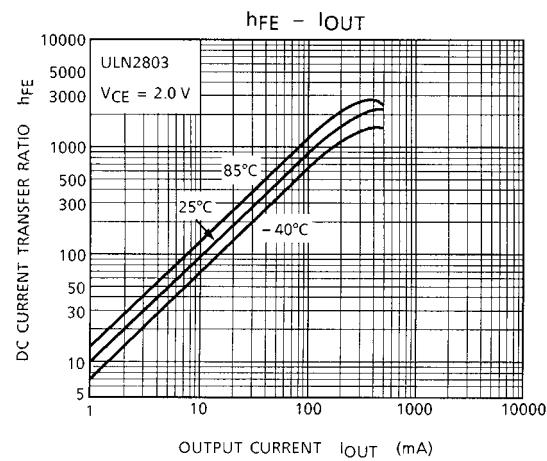
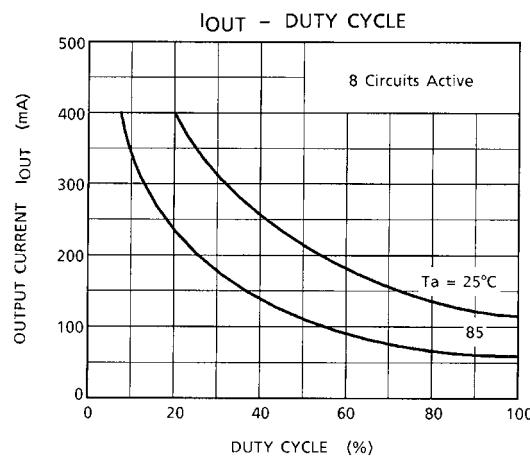
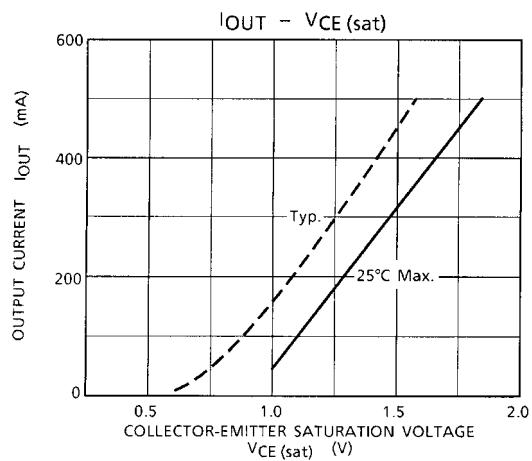
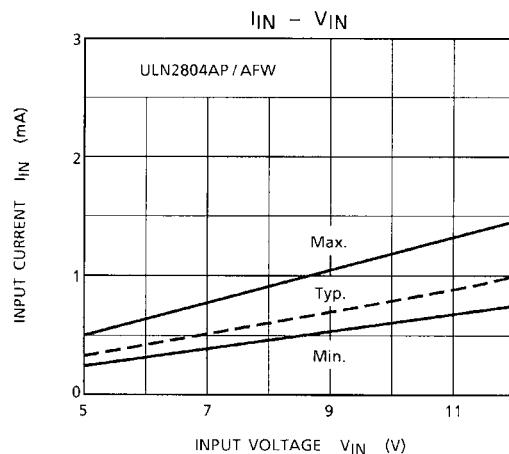
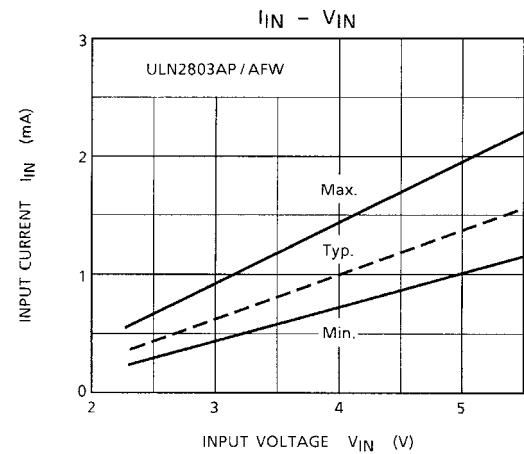
Note 3: C_L includes probe and jig capacitance

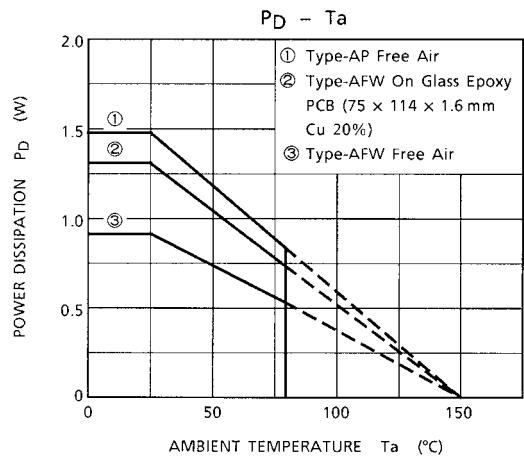
PRECAUTIONS for USING

This IC does not integrate protection circuits such as overcurrent and overvoltage protectors.

Thus, if excess current or voltage is applied to the IC, the IC may be damaged. Please design the IC so that excess current or voltage will not be applied to the IC.

Utmost care is necessary in the design of the output line, COMMON and GND line since IC may be destroyed due to short-circuit between outputs, air contamination fault, or fault by improper grounding.

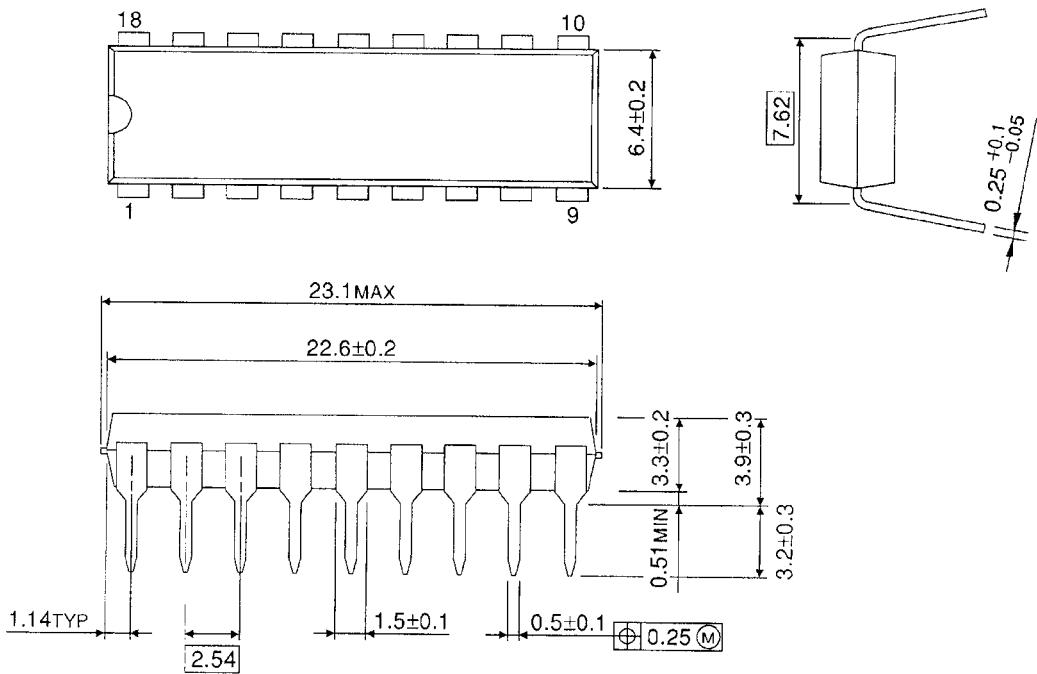




PACKAGE DIMENSIONS

DIP18-P-300-2.54F

Unit: mm

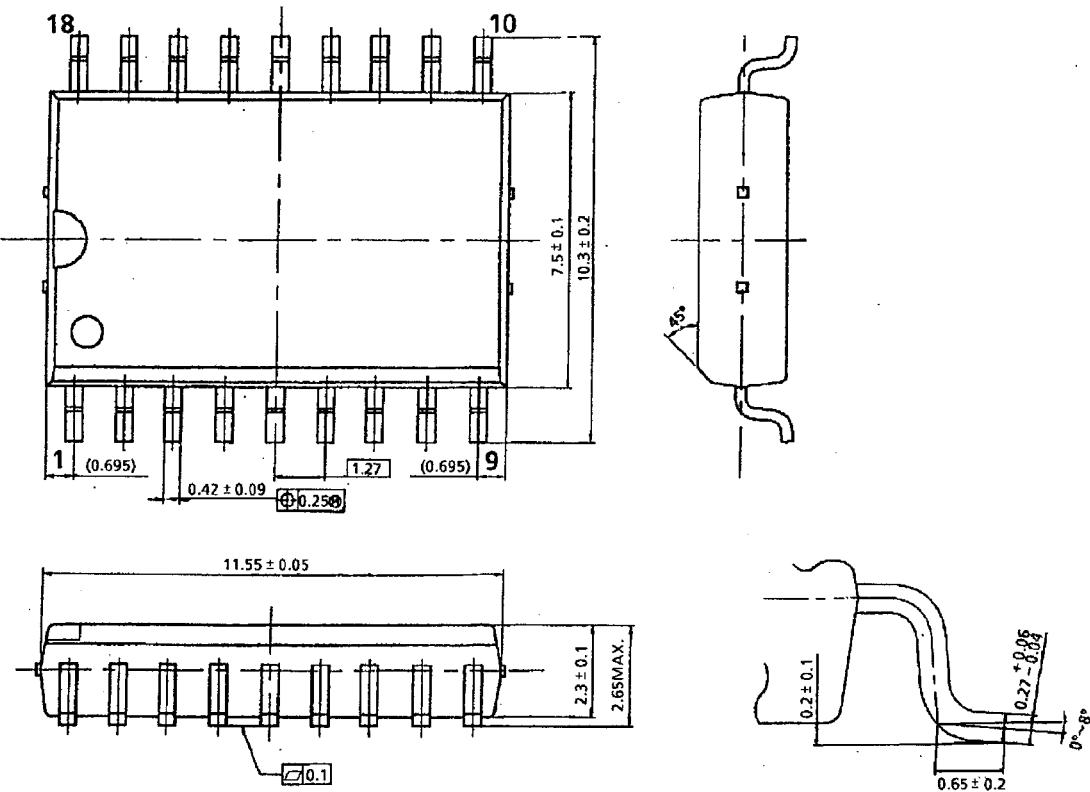


Weight: 1.478 g (Typ.)

PACKAGE DIMENSIONS

SOL18-P-300-1.27

Unit: mm



Weight: 0.48 g (Typ.)

RESTRICTIONS ON PRODUCT USE

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